


<b>Search Notes</b> 	<b>Application/Control No.</b> 10606659	<b>Applicant(s)/Patent Under Reexamination</b> WANG ET AL.
	<b>Examiner</b> IZUNNA OKEKE	<b>Art Unit</b> 2432

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Classification + Keyword search (See History)	10/17/2008	IO
Text Search (See History)	10/18/2008	IO
Search (726/23, 726/24, 726/25) (See History)	10/18/2008	IO
NPL Search (Hashing)	10/16/2008	IO

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--